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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/705,317	11/10/2003	Leo Mathew	SC12733TP	4446	
23125 75	590 07/27/2005		EXAMINER		
	SEMICONDUCTOR,	ROSE, KIESHA L			
LAW DEPART	TMENT ARMER LANE MD:TX3	ART UNIT	PAPER NUMBER		
AUSTIN, TX			2822		
			DATE MAILED, 07/07/2000	_	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applic	ation No.	Applicant(s)				
			5,317	MATHEW ET AL.				
	Office Action Summary	Exami	ner	Art Unit				
		Kiesha	L. Rose	2822				
Period fo	The MAILING DATE of this commun or Reply	ication appears on	the cover sheet w	ith the correspondence ac	idress			
A SH THE - Exte after - If the - If NC - Failu Any	ORTENED STATUTORY PERIOD F MAILING DATE OF THIS COMMUN nsions of time may be available under the provisions SIX (6) MONTHS from the mailing date of this comr o period for reply specified above is less than thirty (3 o period for reply is specified above, the maximum st re to reply within the set or extended period for reply reply received by the Office later than three months ed patent term adjustment. See 37 CFR 1.704(b).	ICATION. s of 37 CFR 1.136(a). In no nunication. sto) days, a reply within the atutory period will apply an will, by statute, cause the	o event, however, may a r statutory minimum of third d will expire SIX (6) MON application to become AB	reply be timely filed by (30) days will be considered time ITHS from the mailing date of this of BANDONED (35 U.S.C. § 133).				
Status								
1)	Responsive to communication(s) file	ed on 30 June 200	5.					
<i>,</i> —	a)⊠ This action is FINAL . 2b)□ This action is non-final.							
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Dispositi	ion of Claims	·	•					
·		application						
-	Claim(s) is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration.							
	✓ Claim(s) 25-28 and 30-38 is/are allowed.							
6)⊠								
	Claim(s) 13-17 and 19 is/are objected	-						
	Claim(s) are subject to restrict		n requirement.					
Applicati	on Papers							
9)[]	The specification is objected to by th	e Examiner.						
-	The specification is objected to by the Examiner. O The drawing(s) filed on is/are: a accepted or b objected to by the Examiner.							
. • , 🗀	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).							
	Replacement drawing sheet(s) including		•	• •	FR 1.121(d).			
11)	The oath or declaration is objected to		-	* * *	, ,			
Priority ι	ınder 35 U.S.C. § 119	•						
12)	Acknowledgment is made of a claim	for foreign priority	under 35 U.S.C. 8	5 119(a)-(d) or (f)				
	 Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) ☐ All b) ☐ Some * c) ☐ None of: 1. ☐ Certified copies of the priority documents have been received. 							
,-								
	2. Certified copies of the priority			oplication No.				
	3. Copies of the certified copies			· •	Stage			
	application from the Internation	•			Ū			
* 5	See the attached detailed Office action	•		received.				
				,				
Attachmen	t(s)							
	e of References Cited (PTO-892)			Summary (PTO-413)				
	e of Draftsperson's Patent Drawing Review (F mation Disclosure Statement(s) (PTO-1449 or			s)/Mail Date nformal Patent Application (PT0	O-152)			
	r No(s)/Mail Date	1 10/36/00)	6) Other:	·	- · · ,			

DETAILED ACTION

This Office Action is in response to the amendment filed 30 June 2005.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-12,20 and 39 are rejected under 35 U.S.C. 102(b) as being anticipated by Lim (U.S. Patent 5,915,176).

Lim discloses a memory device (Figs. 5a-g) that contains forming a semiconductor structure including a top surface, a first sidewall and a second sidewall opposing the first sidewall, a first gate structure (31a) and second gate structure (31b) wherein the first gate structure is located adjacent to the first sidewall and the second gate structure is located adjacent to the second sidewall, a third gate structure (25a) located over the top surface wherein the first, second and third gate structures are physically separate from each other, wherein forming the first gate structure and second gate structure comprises depositing a layer of gate material (31) over both the third gate structure and a substrate (21) and removing a portion of the layer of gate material non-abrasively which overlies the third gate structure to form the first gate structure and second gate structure with a single pattering step, patterning the third gate structure

Application/Control Number: 10/705,317 Page 3

Art Unit: 2822

after depositing the layer of gate material over both the third gate structure and the substrate, patterning the first and second gate structure after removing the portion of the layer of gate material overlying the third gate structure, forming a substantially planar layer overlying the substrate below a height of a top surface of the layer of gate material and using the planar layer as a masking layer to form the first and second gate structure, patterning a first dielectric material separating the semiconductor structure and the third gate structure and two additional layers overlying the third gate structure with the single patterning step, forming a first source/drain region (32) and a second source/drain region (32) extending from the semiconductor structure on opposite sides of the structure orthogonal to sides of the first and second gate structure, wherein the integrated circuit is doped where the first and second source/drain region are located, the first and second source/drain regions are formed by patterning the first, second and third gate structure to expose the first and second source/drain regions, a first dielectric layer (27/28) surrounding the first sidewall and second sidewall and electrically insulating the structure form the first and second gate structures, a second dielectric layer overlying (26) the top surface of the semiconductor structure with a different processing step than the first dielectric layer, the first and second dielectric layers are formed with different dielectric materials and have different thicknesses, forming electrical contacts to the first and second gate structures.

Claim Rejections - 35 USC § 103

Application/Control Number: 10/705,317

Art Unit: 2822

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claim 18 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lim in view of Prinz (U.S. Patent 6,816,414).

Lee discloses all the limitations except for a charge storage structure. Whereas Prinz discloses a memory device (Fig. 2) that contains a first gate (52 on left) formed along a first sidewall, a second gate (52 on right) formed along a second sidewall, a third gate (44) formed on substrate (14) with a source (30), a drain (32), a first charge storage structure (46/48/50 on left) located adjacent to the first sidewall, the first gate structure located adjacent to the first charge storage structure on an opposite side of the first charge storage structure from the first sidewall, a second charge storage structure (46/48/50 on right) located adjacent to the second sidewall, the second gate located adjacent to the second charge storage structure on an opposite side of the second charge storage structure from the second sidewall. The charge storage structure is formed to store charge from the gates. (Column 2, lines 11-26) Therefore it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Lim by incorporating a charge storage structure to store charge from the gates as taught by Prinz.

Claim 21 is rejected under 35 U.S.C. 103(a) as being unpatentable over Lim in view of Cheng et al. (U.S. Publication 20050112817).

Application/Control Number: 10/705,317 Page 5

Art Unit: 2822

Lim discloses all the limitations except for a contact on the third gate. Whereas Cheng discloses a semiconductor device (Figs. 6I and 7) that contains a gate (608) with an electrical contact (750) formed thereon. The electrical contact is formed on the gate to form an electrical contact. Therefore it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Lim by incorporating an electrical contact on the gate to form an electrical connection from the gate to the electrical contact.

Claims 22-24 are rejected under 35 U.S.C. 103(a) as being unpatentable over Lim in view of Cleeves et al. (U.S. Patent 6,580,124).

Lim discloses all the limitations except for the first, second and third gates to have different conductivities. Whereas Cleeves discloses a semiconductor device (Fig. 1b) that contains a semiconductor structure with first and second sidewalls with first and second gate (119)(p type) and a third gate (N+ poly) where the first and second gates are angle implanted with different conductivities (Fig. 2e). The gates have different conductivity types because doping a layer with different materials to get different conductivity is well known in the art. Therefore it would have been obvious to one having ordinary skill in the art at the time the invention was made to modify the device of Lim by incorporating the first, second and third gates to have different conductivities since changing the conductivity is well known in the art.

Claims 13-17 and 19 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Claims 25-28 and 30-38 are allowed.

The following is an examiner's statement of reasons for allowance: Claims 25-28 and 30-38 are allowable because prior art does not show alone or in combination along with the limitations of the independent claim such as a first charge storage structure located between the top surface and the third gate structure.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Response to Arguments

Applicant's arguments with respect to claims 1-28 and 30-39 have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP

Application/Control Number: 10/705,317

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Art Unit: 2822

§ 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kiesha L. Rose whose telephone number is 571-272-1844. The examiner can normally be reached on M-F 8:30-6:00 off 2nd Mondays.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on 571-272-1852. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Application/Control Number: 10/705,317

Art Unit: 2822

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

KLK

Michael Trinh Primary Examiner

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Page 8